



# Influence of ZnO Surface Modification on the Photocatalytic Performance of ZnO/NiO Thin Films

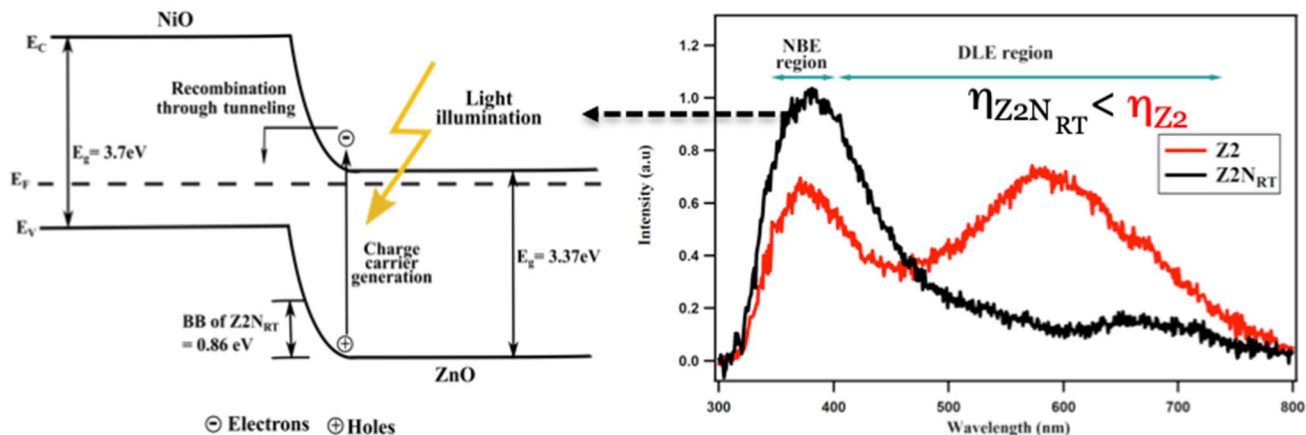
Shanmugapriya Periyannan<sup>1,2</sup> · Laura Mancieri<sup>1</sup> · Ngoc Duy Nguyen<sup>3</sup> · Andreas Klein<sup>2</sup> · Wolfram Jaegermann<sup>2</sup> · Pierre Colson<sup>1</sup> · Catherine Henrist<sup>1</sup> · Rudi Cloots<sup>1</sup>

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## Abstract

Charge carrier separation is considered as a key factor in enhancing the photocatalytic process and can be maximized by mitigating surface recombination. Following this idea, the surface of zinc oxide (ZnO) was modified by thermal treatment and nickel oxide (NiO) deposition. The influence of the ZnO thermal treatment and NiO deposition conditions on the ZnO surface chemistry and heterostructure interface properties were investigated by in situ X-ray photoelectron spectroscopy (XPS) and photoluminescence (PL) and correlated to the dye photodegradation efficiency. The XPS analysis confirmed a change of doping of ZnO after thermal treatment, which mainly influenced the developed band bending, and has led to an improved photocatalytic activity. For the same reason, the heterostructures based on the surface cleaned ZnO surface had higher photocatalytic efficiency than the ones based on non-cleaned ZnO. The temperature input during NiO deposition had negligible effect on the heterostructure interface properties. The photocatalytic efficiency did not follow the band bending evolution because of a dominant contribution of charge recombination across the NiO layer as indicated by PL analysis.

## Graphical Abstract



**Keywords** Heterogeneous catalysis · Catalysis · Thin films · Methodology and phenomena · XPS · Microscopy · Spectroscopy and general characterisation · Photoluminescence · ZnO/NiO · Surface modification · Band bending · Photocatalytic activity

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Extended author information available on the last page of the article

## 1 Introduction

Nanostructured metal-oxide semiconductors have been widely investigated, being employed in a variety of prospective applications that either address environmental issues or

fulfil human needs. Photocatalysis is one among them [1–4]. This process enables the production of electron–hole pairs through light absorption [5]. These photochemical, redox, reactions can be effectively used to tackle environmental problems such as water pollutant degradation, air purification, self-cleaning surfaces or energy generation by water splitting [6, 7]. Metal oxide semiconductors are believed to be promising as photocatalysts since they possess favourable band gap, ideal electronic structure and optical properties. However, their performances as stand-alone materials are limited by the short lifetime of the photo-induced charge carriers [8, 9]. Surface modification techniques like doping, visible light sensitization, metal loading and heterostructure formation are required to overcome these limitations [10].

A typical photocatalytic process involves three vital charge kinetics steps: (i) charge carrier generation, (ii) effective charge transfer and separation and (iii) effective charge consumption [11]. They are interdependent with each other and compromising any of these steps will result in slower kinetics, thereby affecting the efficiency. Therefore, one needs to pay closer attention to the overall structure engineering (surface + interface + band alignment) of the photocatalyst while designing it [12].

Photocatalysts are employed either as powders or thin films based on the requirements. For pollutant degradation, powders have been extensively studied owing to their higher surface to volume ( $S/V$ ) ratio but they have some limitations such as recombination losses, material recovery and reusability issues [13]. Although thin films do not necessitate a complex retrieval process and allow easy reusability, they suffer from lower  $S/V$  ratio. In order to achieve efficient photocatalytic activity in films, surface area needs to be enhanced and one of the strategies is adopting a one-dimensional (1D) nanostructure. Also, these structures are advantageous over planar architectures because of the flexibility to tune their dimensions and packing density during growth, they have strong light trapping effect and allow maximizing absorption with much less material [14]. Furthermore, a heterostructured design is required (irrespective of powder or thin films) for boosting the charge separation.

There are several categories of heterostructures or heterojunctions that can be formed: (i) semiconductor–semiconductor (S–S), (ii) semiconductor–metal (S–M), (iii) semiconductor–carbon (S–C) and (iv) multicomponent heterojunction [15].

Zinc oxide (ZnO) is a n-type metal oxide semiconductor, known for its wide bandgap of 3.37 eV and for its unique optoelectronic characteristics like high exciton binding energy of 60 meV, high electron mobility, good thermal stability and better photosensitivity (compared to other semiconductors). Its other advantages include low cost and natural abundance, lack of toxicity, versatility in synthesis and ease of crystallization [16]. Heterostructure formation

apart from protecting the ZnO from corrosion, improves the charge separation properties [17, 18]. So far, various metal oxide semiconductors including  $\text{TiO}_2$ ,  $\text{BiVO}_4$ ,  $\text{Fe}_2\text{O}_3$ ,  $\text{SnO}_2$ ,  $\text{CdS}$ ,  $\text{Cu}_2\text{O}$  and NiO have been used as second material in heterostructures with ZnO either for pollutant degradation or water splitting applications [19, 20]. Nickel oxide (NiO) is a p-type material with a wide bandgap of 3.7 eV and excitation energy of 110 meV with favorable electronic structure and optical properties. It is capable of acting as a good hole transport layer in addition to its ability to act as an electron-blocking layer [21] stirring our choice for the second material. In this study, ZnO nanorods [ZNR] (250–300 nm long and 50–60 nm wide) were hydrothermally grown on F:SnO<sub>2</sub>/glass substrates and covered (decorated) by a very thin layer of NiO (< 10 nm) by sputtering, targeting photocatalysis applications. This way of preparing the ZnO/NiO heterostructures was never reported for dyes photodegradation. Li et al. [22] reported the fabrication of NiO/ZnO heterostructures for UV detection applications by sputtering much more thicker NiO (150–450 nm) layers on top of chemically grown ZNR (700 nm long and 50 nm wide). No correlation with a precise application was realized. Echresh et al. [23] prepared ZnO/NiO heterostructures by thermally evaporating NiO (50 nm) onto hydrothermally grown ZnO nanorods. The nanorods were completely covered at the top resulting in an evident loss of specific surface which in exchange did not impact their photoresponse. They correlated the drop in the deep level emission and the constant NBE efficiency with the lower dark current. The improved photocurrent was related to the enhanced charge separation without further insight into the interface properties.

Although ZnO/NiO heterostructures with a structure similar [22–24] or different (planar ZnO-600 nm on top of planar NiO-500 nm [25], ZnO@NiO core–shell heterostructures [18], ZnO/NiO hollow nanofibers [17], flower-like ZnO decorated with cubic NiO particles [26], ZnO/NiO composite ( $\mu\text{m}$  range/nm range) powders [27]) than ours were prepared by entirely chemical [18, 24, 26, 27], entirely physical [25] or combined processes [23], most of the time the improvement in the photocatalytic response is more readily related to an enhancement in specific surface. All the previously cited reports fail to simultaneously and comprehensively correlate the photodegradation results with the surface (presence/absence of adsorbates and defects) and interface (Fermi level position, band bending) properties. For example, Ding et al. [18] have prepared ZnO–NiO core–shell heterostructures with high photocatalytic efficiency and reusability via electrochemical deposition on carbon fibre cloth substrates. In this case the variation of the photocatalytic activity with the NiO layer thickness is directly correlated with the specific surface. The reduction in the PL intensity (the deep level emission is not shown) is attributed to the decreased band to band recombination however a measure of

the attained band bending is not given. In another example, ZnO/NiO hollow nanofibers with improved photocatalytic activity [17] were fabricated by impregnating electrospun polyethersulfone (PES) nanofiber webs in nickel and zinc acetate solutions and subsequent thermal treatment. The improved photocatalytic efficiency was attributed to the efficient separation of photogenerated electron–hole pairs without a measure of the attained band bending. Moreover, the difference in specific surface between the composite and the single material fibres is not shown.

Moreover, previous reports on single ZnO or Ag(TiO<sub>2</sub>)/ZnO films have often shown a maximum efficiency of 30–40% [28–32].

Since a clean scaffold material is important in order to achieve a high quality interface that will allow effective quantum confinement (an effect, which confines or localizes the movement of electrons as a result of nano scale material) in the heterostructure [33], we have employed a post-processing thermal treatment on ZNR prior to NiO deposition. For the same reason, the deposition conditions for NiO layer were also varied. The correlation of X-ray photoelectron spectroscopy (XPS) and photo luminescence (PL) with the photodegradation results allowed understanding the role of the external factors, like ZnO surface cleaning and NiO deposition conditions, on the scaffold surface chemistry and consequently on the internal factors (band bending, ratio of shallow vs. deep level defects) on the photocatalytic response.

## 2 Materials and Methods

All the samples were grown on FTO glass substrates purchased from Dyesol (15 W/sq.). Before use, the substrates were cleaned for 15 min each with acetone and then ethanol, by using an ultrasound bath.

### 2.1 ZnO Nanorod Arrays (ZNR) Preparation by Two-Step Chemical Route

Step 1: Seeding layer preparation: 0.68 g of zinc acetate dihydrate (Sigma Aldrich, 99%) and 225  $\mu$ L of ethanolamine stabilizing agent, (Sigma Aldrich, 99.5%) were added to 15 mL ethanol (VWR, 99.8%), to result in 250 mM solution. This mixture was stirred at 60 °C for an hour and the stirring was further continued at room temperature (RT), for 24 h. Then 500  $\mu$ L of the homogeneous solution were spin coated on FTO substrates at 3000 rpm, for 20 s (the relative humidity RH was maintained at 35% during the coating process). This process was repeated 5 times, to ensure complete coverage of the substrate with seeds. The seeded substrates were annealed at 500 °C for 2 h (heating ramp = 300 °C/h).

Step 2: Nanorod growth: 0.072 g of zinc nitrate hexahydrate (Sigma Aldrich, 99%) and 0.052 g of hexamethylenetetramine (Sigma Aldrich, 99.5%) were added to 15 mL of milliQ water and stirred until a homogeneous solution was obtained, which was later transferred to a Teflon lined autoclave. The seeded substrate was immersed in the solution in a tilted position, with the coating facing downward. The hydrothermal process was carried out at 92 °C, for 1 h. Afterwards the samples were washed with distilled water, dried in oven at 60 °C for 30 min and finally annealed at 500 °C for 2 h.

### 2.2 ZnO Surface Modification

Z1 and Z2 are the ZNR scaffold surfaces without and with surface cleaning treatment respectively. The surface cleaning treatment was carried out inside the sputtering chamber in a controlled, static oxygenated atmosphere (1 h at 400 °C, 0.5 Pa, O<sub>2</sub> flow 5 sccm) for removing the unwanted adsorbates. The ZnO/NiO heterostructured films were prepared by depositing NiO onto scaffold surfaces Z1 and Z2 and the respective samples were denominated as Z1N and Z2N. NiO deposition was done by direct current (DC) magnetron sputtering using a Ni target (99.99% purity), for 40 s, in the presence of argon (Ar) and oxygen (O<sub>2</sub>) gases and the substrate was placed at a distance of 9.5 cm from the target and the relative oxygen partial pressure was maintained at 6%. The pressure inside the sputtering chamber was set to 0.5 Pa. Sputtering was performed using a DC power of 40 W, in different temperature conditions: RT deposition, RT deposition followed by post annealing (PA) at 250 °C and high temperature (HT, T = 400 °C) deposition. Correspondingly, the RT, PA and HT indices were added (as subscript) to the sample codes.

### 2.3 Photodegradation Experiments

All the degradation experiments were carried out with 20 mL (1.3  $10^{-6}$  M, i.e. 13  $\mu$ g) of Rhodamine-B—RhB (Sigma Aldrich, 95%) solution. The prepared substrates were cut into 1 cm  $\times$  1 cm that supported around 0.13 mg of ZnO and used in the degradation studies. The ratio between photocatalyst and pollutant used here is 10:1. The ratio usually used for powder photocatalysts is 50:1. Initially, the film was kept under dark for 20 min, with mild stirring, in order to ensure adsorption of pollutants on the surface. It was then exposed to light source for 180 min. Then, 1 mL of aliquot sample was taken at time 0 and then every 20 min and analysed by UV–visible spectrophotometry. This enabled monitoring the pollutant degradation over time and comparing the degradation efficiency of each sample.

## 2.4 Experimental Methods

The X-ray diffraction patterns of the ZNR films were obtained using the Bruker, D8 Diffractometer equipped with a Cu  $\alpha$  radiation source in the grazing incidence mode (incidence angle  $1^\circ$ ) in the  $2\Theta = 20\text{--}70$  range. SEM images were acquired using a FEG-SEM (XL 30, FEI) operated at 15 kV. TEM images were obtained by employing a TECNAI G2 TWIN (FEI) operating at 200 kV. PL emission spectra of ZNR and ZnO/NiO films (examined area =  $2\text{ cm} \times 2\text{ cm}$ ) were acquired by using a Varian Cary Eclipse, Fluorescence Spectrophotometer equipped with a Xenon flash lamp, which was operated at an excitation wavelength of 325 nm, while emissions were recorded in the range of 300–850 nm. XPS was used to investigate the single/heterostructured films surface and electronic characteristics. The measurements were performed using the Darmstadt Integrated System for Materials Research (DAISY-MAT). It is a physical electronics PHI 5700 multi technique surface analysis system combined with thin film deposition (sputtering, atomic layer) chambers, enabled with a vacuum transfer system. The measurement chamber is equipped with a monochromatic Al  $K\alpha$  X-ray source providing photons with  $h\nu = 1486.6\text{ eV}$ . All spectra were measured at a photoelectron take-off angle of  $0^\circ$  (normal emission) and room temperature. Binding energies (BE) of respective elements were obtained calibration with the Fermi edge of sputter cleaned silver (Ag) standard. The Shimadzu UV3600 Plus spectrophotometer was used to measure the absorption spectra of the RhodamineB solution before and after photodegradation.

Degradation studies were carried out under a  $5\text{ mW/cm}^2$  UV light source (maximum wavelength 365 nm), with the sample placed at 18 cm distance from the UV source. RhodamineB (RhB) was used as the model pollutant for investigation. A stock solution of 10 mg/L was prepared and stored in dark. Solution of 1.25 mM was prepared from the stock, to be used during the degradation tests with  $1\text{ cm}^2$  films. The pH was adjusted to 8 for avoiding the dissolution of the ZnO and NiO materials and to render the surface negatively charged ( $\text{pH} > \text{point of zero charge—PZC}$ ,  $\text{ZnO}_{\text{PZC}} = 8.6\text{--}9.2$  and  $\text{NiO}_{\text{PZC}} = 8.6\text{--}10.5$  [34], whereas for ZnO heterostructures -  $\text{PZC} = 7.3\text{--}7.6$ [35, 36]) in order to encourage the dye molecules adsorption. Initially the sample was stirred in dark for 20 min to achieve equilibrium and then exposed to UV light for 3 h. The absorption spectra of RhB were registered every 20 min.

## 3 Results

### 3.1 X-ray Diffraction

The crystallinity and orientation of the hydrothermally grown ZNR were confirmed with X-ray diffraction (Fig. 1).

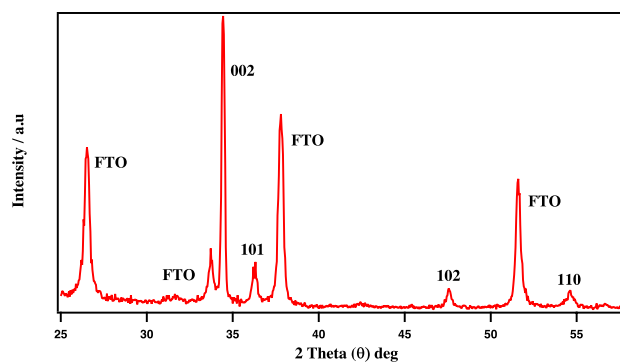


Fig. 1 XRD spectra of ZNR film

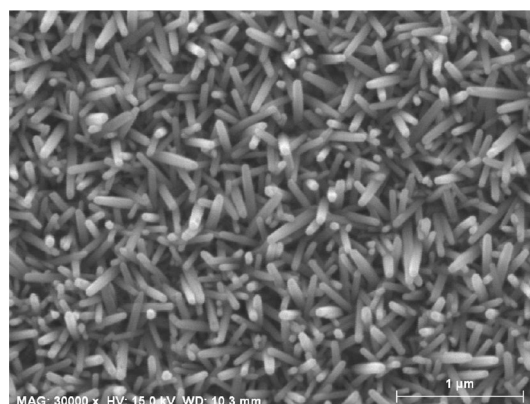


Fig. 2 SEM image of ZNR film

The (002) peak at  $2\Theta = 34.50^\circ$  corresponding to the wurtzite phase of ZNR (JCPDS card no. 79-2205) shows the highest intensity, confirming the one dimensional growth along the c-axis as desired.

### 3.2 Scanning Electron Microscopy

The SEM image of the ZNR showed that densely packed nanorods with random orientation were obtained (Fig. 2). The nanorods were found to be 250–300 nm long and 50–60 nm wide which corresponds to an average aspect ratio of 5. The SEM images of the ZNR film after NiO deposition did not show any changes in the morphology or surface of ZNR. This is due to the fact that the NiO thickness was very low, below 10 nm.

### 3.3 Transmission Electron Microscopy

The image of Z1 (Fig. 3a) confirms the presence of ZnO 1D nanostructure with smooth surface. Through NiO deposition, the surface of nanorods is uniformly covered with a rough layer (Fig. 3b, c) with a thickness in the range of 2–3 nm.



We also noticed that the thickness of NiO layer was higher for PA than that for RT, which might be due to the supplementary post annealing treatment. The image of HT film (Fig. 3d) revealed the formation of cubic nanoparticles of 5–6 nm (zoomed image in inset of Fig. 3d), rather than a layer at the surface of nanorods. Therefore, this indicates that the crystallite size is enhanced due to the slower growth rate. The (111) plane of NiO could be identified from the TEM images (Fig. S1 in Supplementary Information) for all the samples. The TEM images also demonstrate that the NiO layer was capable of covering the ZNR surface throughout its 200–250 nm length, which would increase the visible light absorption [22].

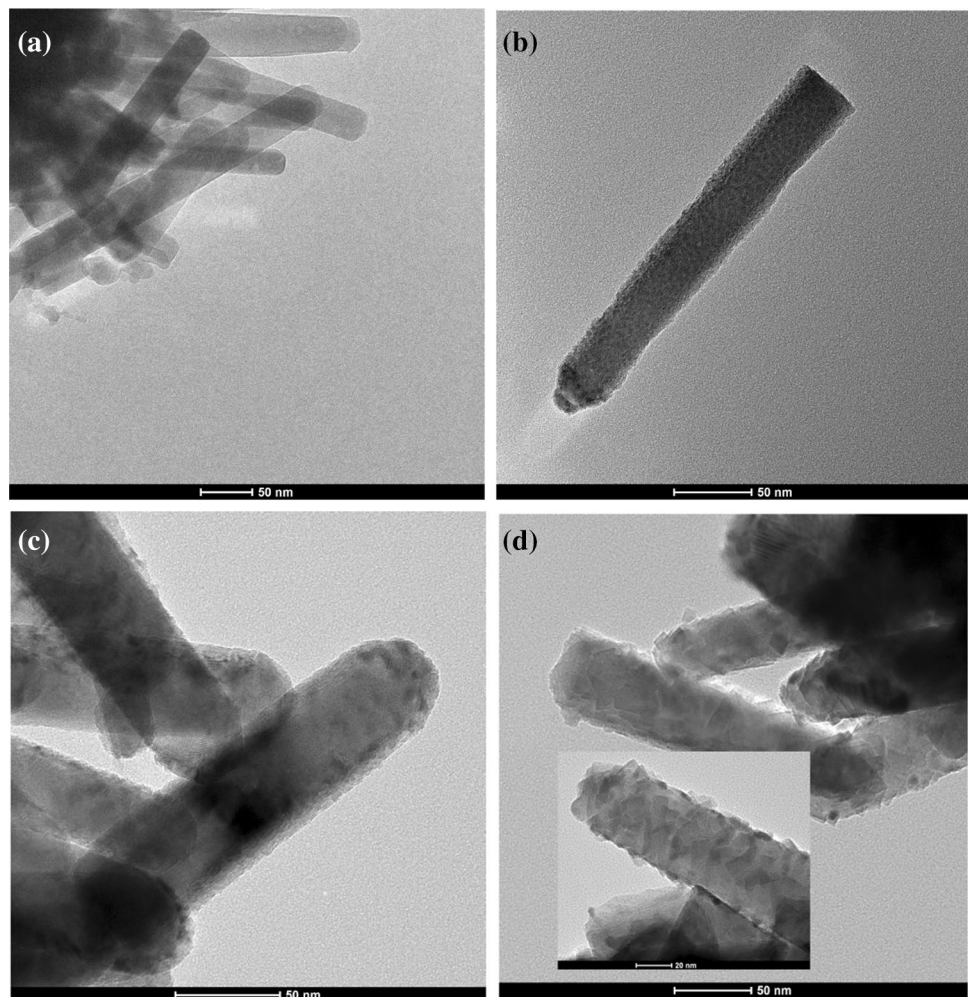
### 3.4 Photo Luminescence

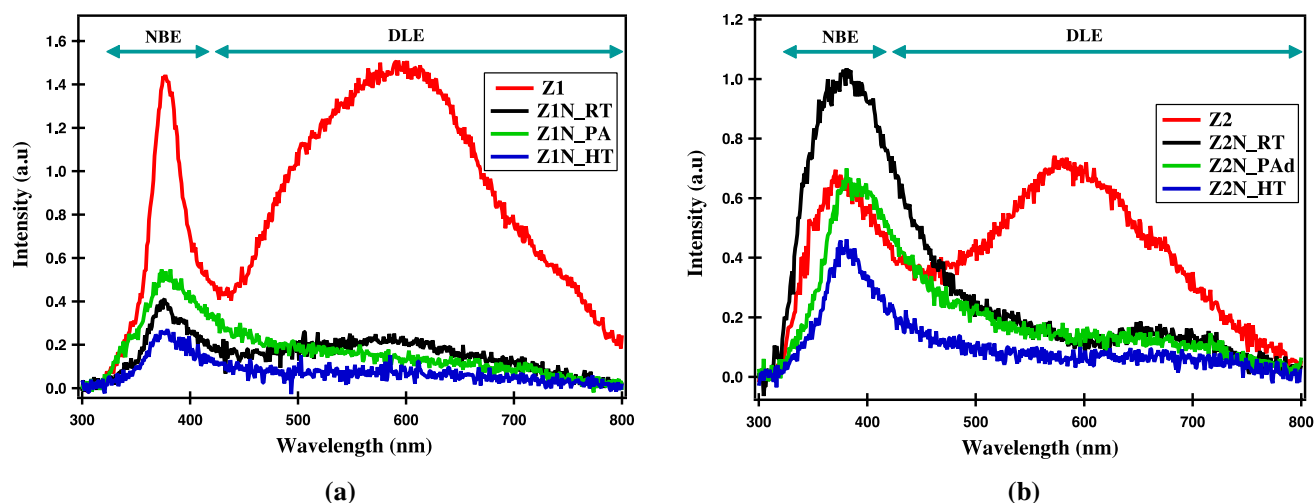
The PL spectra of the single ZNR surfaces without and with surface cleaning treatment (Z1 and Z2, respectively) and their corresponding heterostructures with NiO are shown in Fig. 4a, b, respectively. All the spectra exhibited one peak, in the range of 387–397 nm, attributed to Near Bandedge

Emission (NBE) [37] which corresponds to the recombination due to surface excitons [38], and another one in the range of 450–800 nm, assigned to deep level emission (DLE) [24, 39] which correspond to the deep trap levels in ZnO (here including O/Zn vacancies and interstitials) [40, 41].

For further understanding the contribution of surface excitons and defects in charge carrier recombination, the intensity ratios  $I_{\text{NBE}}/I_{\text{Total}}$  and  $I_{\text{DLE}}/I_{\text{Total}}$  were determined and given in Table 1. For both Z1 and Z2 scaffold, the DLE emission seems to be predominant in the PL spectra (as seen in Table 1). However with surface cleaning, the NBE emission was mildly reduced with respect to the DLE [42, 43] (see Table 1), proving the removal of adsorbates. A higher difference was expected but not observed, due to –OH re-adsorption from the ambience while the sample was transferred to the PL instrument [44, 45]. Also, the concentration of deep level defects was slightly reduced since part of the oxygen vacancies were passivated through surface cleaning [46, 47]. In addition, the blue shift of DLE peak after thermal treatment (from 602 nm for Z1 to 584 nm for Z2)

**Fig. 3** TEM image of **a** Z1 (without surface cleaning), **b** Z1N<sub>RT</sub>, **c** Z1N<sub>PA</sub> and Z1N<sub>HT</sub> [zoomed view in the inset]. RT room temperature, PA post annealed, HT high temperature





**Fig. 4** Photo luminescence spectra of **a** Z1 (without surface cleaning) and corresponding heterostructures and **b** Z2 (surface cleaned) and corresponding heterostructures

**Table 1** Sample codes and corresponding details from PL spectrum and band bending values from XPS spectrum [deduced as detailed in (Sect. 3.5)]

Sample code	NBE peak maximum position (in nm)/shift	FWHM of NBE peak (in nm)	$I_{\text{NBE}}/I_{\text{Total}}$	$I_{\text{DLE}}/I_{\text{Total}}$	Band bending from XPS- $V_{\text{bb}}$ (in eV)
Without surface cleaning (Z1)					
Z1	371	38	0.18	0.82	–
Z1N <sub>RT</sub>	379/Red	50	0.05	0.11	1.12
Z1N <sub>PA</sub>	381/Red	61	0.08	0.08	1.32
Z1N <sub>HT</sub>	379/Red	58	0.04	0.03	0.89
Surface cleaned (Z2)					
Z2	367/Blue	40	0.28	0.71	0.50
Z2N <sub>RT</sub>	372/Red	77	0.45	0.34	0.86
Z2N <sub>PA</sub>	381/Red	48	0.1	0.4	0.79
Z2N <sub>HT</sub>	380/Red	41	0.1	0.11	0.67

$I_{\text{NBE}}$  and  $I_{\text{DLE}}$  values were taken by calculating the corresponding area below the deconvoluted peaks (using a data analysis software, IgorPro). RT—deposited at room temperature; PA—deposited at RT and post annealed at 250 °C for 1 h; HT—deposited at high temperature—400 °C]

suggests that part of the  $V_{\text{O}}$  were ionized through surface cleaning [43, 48–51].

After NiO deposition the intensity of the PL decreased but with a matching contribution from both DLE and NBE (Table 1), suggesting that even if charge separation was enabled, non-radiative recombination across the NiO layer might have occurred. The NBE peaks of all heterostructures were red shifted (Table 1) signifying an enhancement in the quantum confinement effect [39, 52], as a result of nanoscale NiO covering.

In case of sample Z2N<sub>RT</sub>, the red shift and the increase in intensity of NBE peak might indicate an additional effect, apart from the non-radiative recombination across the NiO layer. Additionally, the broadening of the NBE peak (Table 1) as compared to scaffold indicates the presence

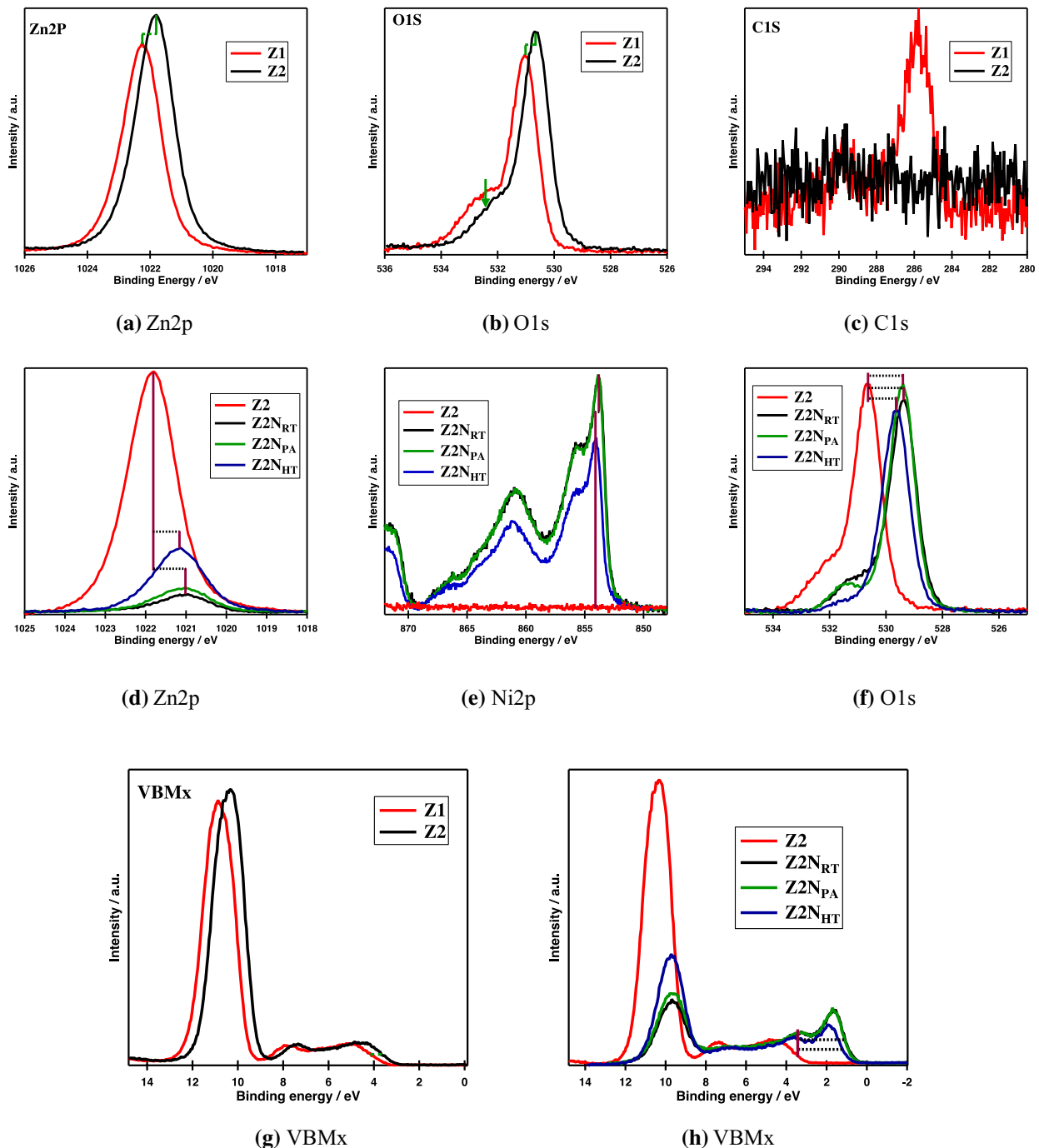
of fluctuations at the interface [53, 54]. This effect was removed by using a cleaned scaffold and NiO deposition at HT, as in the case of sample Z2N<sub>HT</sub>.

### 3.5 X-ray Photo Electron Spectroscopy

As expected, the XPS survey spectra of Z1, Z2 and their corresponding heterostructures (Figure S2 in Supplementary Information) showed the presence of Zn, Ni and O, but also of carbon and hydroxyl species adsorbed on the surface of the Z1 sample [26, 48, 55]. The detailed XPS spectra of Zn2p, Ni2p, O1s lines and valence band for all the samples are shown in Fig. 5 and Figure S3 in Supplementary Information. The spectra of ZnO after synthesis (Z1) and after surface cleaning (Z2) are overall very similar to each other

showing clearly developed Zn2p and O1s lines (Fig. 5a, b and Table S1 in Supplementary Information) and a valence band structure (Fig. 5g), which indicates the formation of ZnO [25]. The shoulder in the O1s line (Fig. 5b, f) at the binding energy (BE) of 532 eV is attributed to –OH adsorbates [48, 56]. A slight shift of the Zn2p BE of about 0.48 eV

(Fig. 5a and Table S1 in Supplementary Information) as well as of the Fermi level (for Z1,  $E_F - \text{VBMx} = 3.47$  eV whereas for Z2,  $E_F - \text{VBMx} = 3.04$  eV, Table S1 in Supplementary Information) after surface cleaning (by heating at 400 °C) was observed. These shifts are attributed to a change in the doping of the sample from a sample which was n+ doped

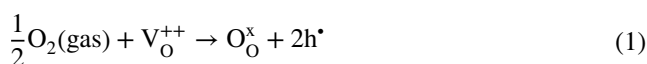


**Fig. 5** Zn2p (a), O1s (b), C1s (c) spectra and VBMx (g) shift for Z1 (without surface cleaning) and Z2 (surface cleaned) scaffold and Zn2p (d), Ni2p (e), O1s (f) spectra and VBMx (h) shift for the Z2

(surface cleaned) scaffold compared with its corresponding heterostructures. *RT* room temperature; *PA* post annealed, *HT* high temperature

to a sample which is n- doped. In principle, we cannot discriminate in these experiments a bulk doping from a surface doping but assume a change of bulk doping because of the small thickness of the nanorods (diameter  $\approx$  50–60 nm). The increase in intensity of all peaks, the absence of carbon peak and reduction of intensity in the oxygen shoulder peak for Z2 compared to Z1 (Fig. 5a, c) confirmed the effective removal of adsorbents ( $-\text{OH}$ ) through surface cleaning [56].

The shift in VBMx binding energy (Fig. 5g, h) revealed that the Fermi level was positioned above the conduction band (CB) for Z1 (without surface cleaning,  $E_{\text{F}} - \text{VBMx} = 3.47$  eV, Table S1 in Supplementary Information) and it was shifted below CB ( $E_{\text{F}} - \text{VBMx} = 3.04$  eV) after surface cleaning treatment (for Z2) in the presence of oxygen. This clearly indicates that part of the oxygen vacancies in Z1 (without surface cleaning) were filled by incoming oxygen (Eq. 1) in case of Z2 (surface cleaned) sample [57, 58].



With the deposition of NiO, the typical features and satellite structure of  $\text{Ni}^{2+}$  and O were observed [25] (Fig. 5e, f and Figures S3b and S3c in Supplementary Information). Also, the XPS valence band feature shows the typical spectral signature of NiO (Fig. 5h and Figure S3d in Supplementary Information). However, even for HT conditions, no modification of the satellite peak is detected (Fig. 5e and Figure S3b in Supplementary Information), meaning that the formation of  $\text{Ni}^{3+}$  is likely improbable.

Band bending ( $V_{\text{bb}}$ ) of the substrate was determined using the Eq. 2 [59–62], that involved subtraction of core level binding energies of substrate or scaffold material (here, Zn2p) at initial step [ $\text{BE}_{\text{Zn2p}}(i)$ ] and after surface modification or growing of the NiO film [ $\text{BE}_{\text{Zn2p}}(f)$ ]. The  $V_{\text{bb}}$  values are given in Table 1.

$$V_{\text{bb}} = \text{BE}_{\text{Zn2p}}(i) - \text{BE}_{\text{Zn2p}}(f) \quad (2)$$

If we compare the observed changes in  $V_{\text{bb}}$  as well as the changes in relative intensities [25] of Zn2p peak (Table S1 in Supplementary Information) after NiO deposition (Fig. 5d–f and Figure S3a to S3c in Supplementary Information), a clear trend cannot be extracted that could be related to modification of the growth process of the co-catalyst, neither to changes in the doping of the scaffold. However, some general conclusions can be deduced. The overall shift in BE that led to a larger band bending for the Z1 heterostructures as compared to the Z2 ones, due to its higher n+ doping. The NiO deposition at high temperatures on Z1 and Z2 scaffold shows a larger  $E_{\text{F}} - \text{VBMx}$  difference (0.84–0.95 eV, Table S1 in Supplementary Information) compared to RT and PA depositions (0.66 eV, Table S1 in Supplementary Information), which can be related to a better-defined

stoichiometry. Overall, a clearly developed band bending ranging from 1.3 to 0.7 eV (Table 1) is found after NiO deposition.

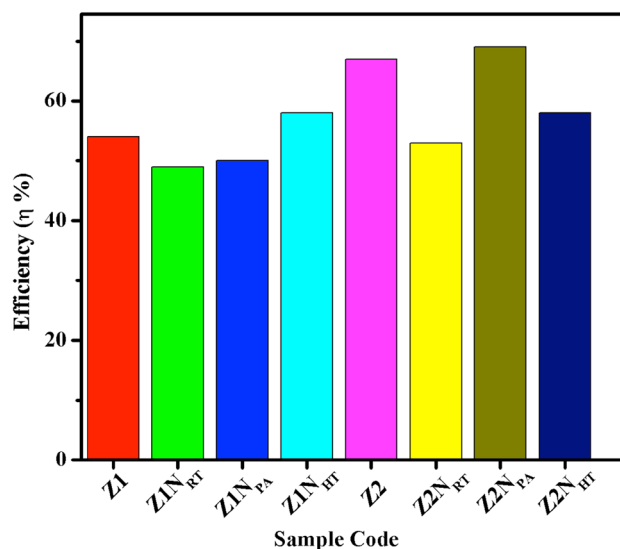
### 3.6 Pollutant Degradation

The degradation efficiency for each sample (after 180 min) was calculated according to Eq. 3 and shown in Fig. 6. The evolution of  $C_t/C_0$  as function of time is shown in Figure S4 in Supplementary Information.

$$\text{Efficiency}(\eta)\% = \left(1 - \left(\frac{C_t}{C_0}\right)\right) \times 100 \quad (3)$$

where  $C_t$  is the concentration in time;  $C_0$  is the initial concentration. The photocatalytic control experiment was carried in light in the presence of Rhodamine-B, without photocatalyst. After exposure in UV light for 180 min. No signs of degradation were observed (Fig. S5 in Supplementary Information).

Z1 was able to degrade 54% of the pollutant whereas, its heterostructures were found to have lower performance, except for HT whose efficiency was 58%. We believe that four competing mechanisms influence the photodegradation efficiency: (1) the holes photogeneration which is favoured for low NiO thickness, (2) charge recombination which is expected to be enhanced when  $V_{\text{bb}}$  is reduced, (3) ZnO interface charge recombination because of defects and (4) charge recombination across the NiO layer. Though the variation of photocatalytic efficiency in Z1 heterostructures cannot



**Fig. 6** Pollutant degradation efficiencies of Z1 (without surface cleaning), Z2 (surface cleaned) and their corresponding heterostructures. Degradation study was conducted for three samples of scaffold Z1 (without surface cleaning) and resulted in an error bar of 2%. RT room temperature, PA post annealed, HT high temperature



be explained by a simple combination of these arguments, it is obvious in case of sample Z1N<sub>HT</sub> that mechanism (1) is prevailing. Concurrently, the Z2 heterostructures were overall more efficient than their Z1 counterparts, with the highest efficiency obtained for the Z2N<sub>PA</sub> (69%) but with similar activity with the Z2 scaffold. From here we conclude that limiting the contribution of mechanism (3) by surface cleaning is mostly influencing the photocatalytic efficiency and the modest or lack of improvement after NiO deposition might be influenced by mechanism (4), which could be due to a thin space charge layer.

Recent reports have demonstrated that post processing of ZnO or heterostructure formation enhanced photocatalytic activity due to reduction in surface/bulk defects and improved charge separation [14, 15]. This was also correlated with the photoluminescence response but with inconsistent conclusions; reduction [30, 63, 64] and increase [22, 38] in the NBE emission were both related to an enhancement in photocatalytic activity. The PL, XPS and RhB photodegradation allowed us to conclude that in order to obtain a better efficiency, charge separation should be effective (high band bending) which is correlated to the PL emission diminution but also to non-radiative recombination across NiO layer should be avoided by increasing the width of the space charge layer.

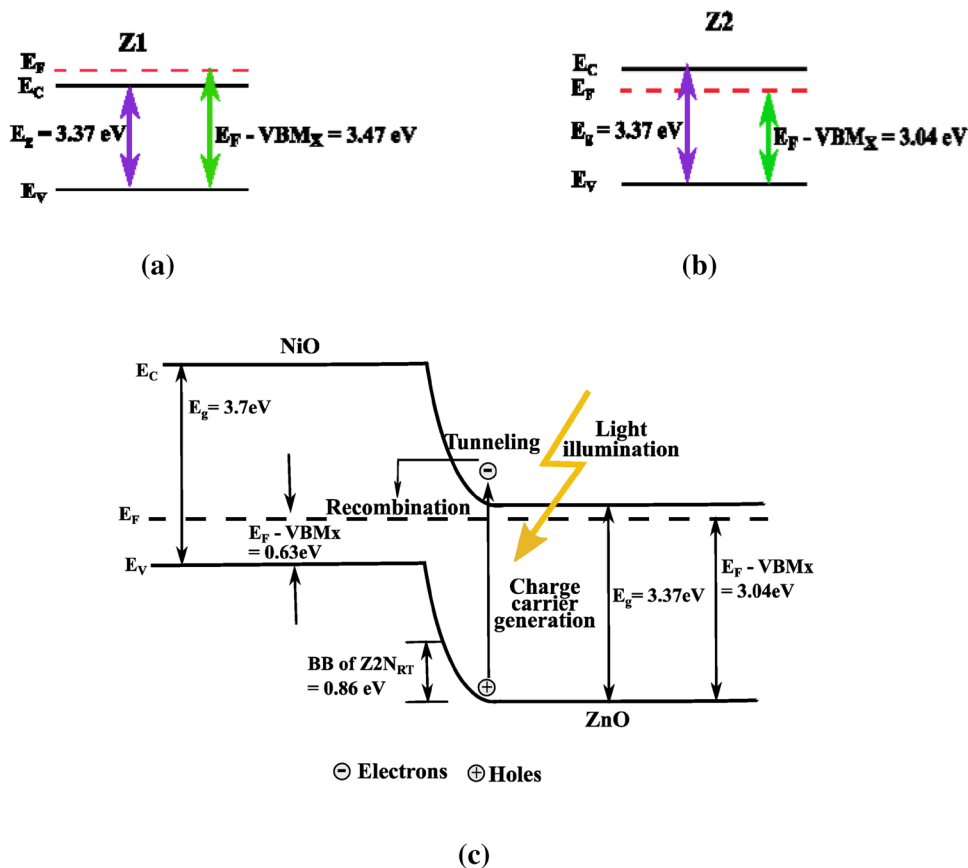
### 4 Discussion

The XPS measurements of Z1, Z2 and their respective heterostructures (Fig. 5 and Supplementary Figure S3) have been used to determine the Fermi level positions and band bending attained for each sample. In case of Z1 scaffold the position of the Fermi level is above the CB (Fig. 7a) which causes a downward band bending and thus the formation of an e<sup>-</sup> accumulation layer. In case of the Z2 scaffold the Fermi level position was shifted below CB after surface cleaning treatment (Fig. 7b), followed by band flattening due to e<sup>-</sup> depletion [51].

Bringing n-type ZnO and p-type NiO material into contact resulted in the formation of a space charge region at the interface and thus band bending (example shown for Z2N<sub>RT</sub> in Fig. 7c, E<sub>F</sub> - VBM<sub>X</sub> values from Table S1 in Supplementary Information). The maximum band bending obtained for Z1 heterostructures was 1.3 eV, higher than for Z2 heterostructures (0.86 eV). However, the pollutant degradation process emphasized that larger band bending does not generally lead to higher photodegradation efficiency.

These results might be in contrary to previous literature reports where heterostructures were shown to be

**Fig. 7** Band energy diagram of Z1—without surface cleaning (a) and Z2—surface cleaned (b), band alignment and band bending for Z2N<sub>RT</sub> (c) [RT room temperature]. E<sub>F</sub> - VBM<sub>X</sub> values as obtained from the respective XPS spectra



photocatalytically more active as a consequence of charge separation induced by interfacial band bending [14, 15]. The optimal band bending (height and width of the space charge layer) and its influence on photocatalytic response were not reported in literature previously. Thus, for a detailed discussion of space charge layer effects in charge carrier separation, all aspects of heterostructure preparation must be taken into consideration. Due to the high doping of the ZnO scaffold, which is an indication of large concentration of bulk/surface defects, the width of the space charge layer shown in Fig. 7c is very small. As a consequence, charge carriers are not evidently separated due to the contact but instead recombine via the NiO layer by tunnelling through the extremely thin interface barrier. This mechanism can explain the low catalytic efficiencies obtained for Z1 based samples and the modest improvement in the efficiencies of Z2 samples as here the doping concentration is reduced.

These conclusions are also supported by the PL data, represented in Sect. 3.4. In all samples we observe a high contribution of defect states as recombination centers. These defect states may also be involved in the electron–hole recombination across the NiO contact layer due to increased rate of electron transfer across the space charge layer. The strong reduction in the overall photoluminescence intensity after NiO deposition, but with an almost equal contribution from deep level and surface defects (Table 1), can also be taken as clear argument for the above formulated hypothesis describing a dominating influence of electron–hole recombination vs. electron–hole separation.

In conclusion, our results indicate that there is a fine balance between appropriate band bending, a good quality interface and the reduction of charge recombination. Such a balance was only attained for the Z2 samples mainly as a result of surface cleaning treatment, with little influence from the NiO deposition conditions due to recombination across the NiO layer.

## 5 Conclusion

ZnO surface was modified by heat treatment in O<sub>2</sub> atmosphere and then sputtered NiO (p-type) onto chemically grown 1D ZnO (n-type). The influence of ZnO surface cleaning and NiO deposition conditions on the heterostructure formation and final performance in dye degradation was studied. The XPS study of the bare ZnO revealed that the Fermi level of the as-prepared ZnO surface which was above the conduction band (CB) shifted inside the bandgap after surface cleaning treatment. This confirms that the doping of ZnO was changed but the PL results alone cannot discriminate if this has taken place at the surface or in the bulk. By correlating XPS and PL with the photodegradation activity

we were able to conclude that the improved photo-catalytic performance of Z2 samples compared their Z1 counterparts was mostly the consequence of surface cleaning. Indeed, the modest performance of the heterostructures compared to the scaffolds indicates that the charge separation after NiO deposition was not as effective as it would have been expected from the band bending values ( $V_{bb}$  in the range of 0.7 to 1.3 eV) because of charge recombination inside the NiO layer (PL results show that DLE and NBE contributions were equally present no matter the deposition conditions). The highest photocatalytic efficiency among the Z2 heterostructures was obtained for sample Z2N<sub>PA</sub> for which the developed NiO layer thickness allowed the mitigation of the tunnelling effect. Therefore our study demonstrates that the correlation of a high band bending or PL emission quenching/increase with the improved photocatalytic efficiency is not straightforward and other factors must be considered when tuning the band bending such as the materials doping level, the space charge layer thickness, the co-catalyst thickness, etc., in order to maximize the photocatalytic efficiency.

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## Compliance with Ethical Standards

**Conflicts of interest** The authors declare no conflict of interest.

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## Affiliations

Shanmugapriya Periyannan<sup>1,2</sup> · Laura Mancneriu<sup>1</sup> · Ngoc Duy Nguyen<sup>3</sup> · Andreas Klein<sup>2</sup> · Wolfram Jaegermann<sup>2</sup> · Pierre Colson<sup>1</sup> · Catherine Henrist<sup>1</sup> · Rudi Cloots<sup>1</sup>

✉ Shanmugapriya Periyannan  
speriyannan@uliege.be; periyannan@surface.tu-darmstadt.de;  
priya1988infotech@gmail.com

<sup>1</sup> GREENMAT-LCIS, CESAM Research Unit, Institute of Chemistry, Universite de Liege, B6, Sart Tilman, 4000 Liege, Belgium

<sup>2</sup> Surface Science Division, Institute of Materials Science, Technische Universitat Darmstadt, Otto-Berndt-Strasse 3, 64287 Darmstadt, Germany

<sup>3</sup> SPIN, CESAM Research Unit, Institute of Physics, Universite de Liege, B5, Sart Tilman, 4000 Liege, Belgium